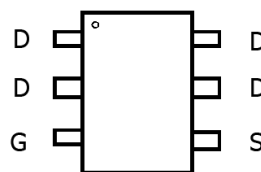
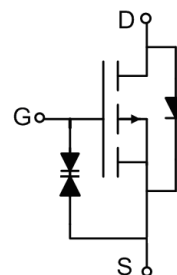


**Main Product Characteristics:**

$V_{DSS}$	-20V
$R_{DS(on)}$	38m $\Omega$ (typ.)
$I_D$	-5.5A ①


**SOT-23-6**

**Marking and pin Assignment**

**Schematic diagram**
**Features and Benefits:**

- Advanced MOSFET process technology
- Special designed for PWM, load switching and general purpose applications
- Ultra low on-resistance with low gate charge
- Fast switching and reverse body recovery
- 150°C operating temperature


**Description:**

It utilizes the latest processing techniques to achieve the high cell density and reduces the on-resistance with high repetitive avalanche rating. These features combine to make this design an extremely efficient and reliable device for use in power switching application and a wide variety of other applications.

**Absolute max Rating: @ $T_A=25^\circ\text{C}$  unless otherwise specified**

Symbol	Parameter	Max.	Units
$I_D$ @ TC = 25°C	Continuous Drain Current, $V_{GS}$ @ 10V	-5.5 ①	A
$I_D$ @ TC = 70°C	Continuous Drain Current, $V_{GS}$ @ 10V	-4 ①	
$I_{DM}$	Pulsed Drain Current ②	-30	
$P_D$ @TC = 25°C	Power Dissipation ③	2.1	W
$V_{DS}$	Drain-Source Voltage	-20	V
$V_{GS}$	Gate-to-Source Voltage	$\pm 8$	V
$T_J$ $T_{STG}$	Operating Junction and Storage Temperature Range	-55 to +150	°C

**Thermal Resistance**

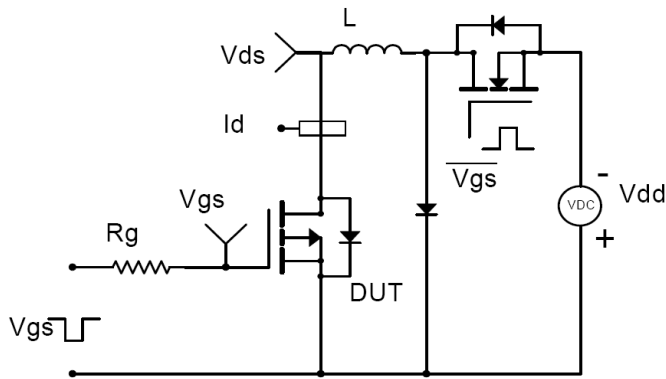
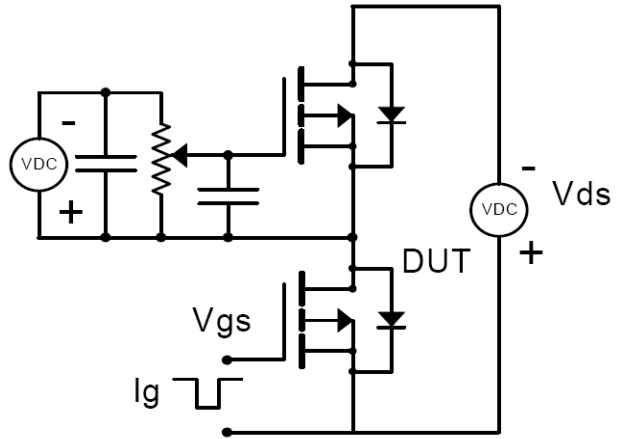
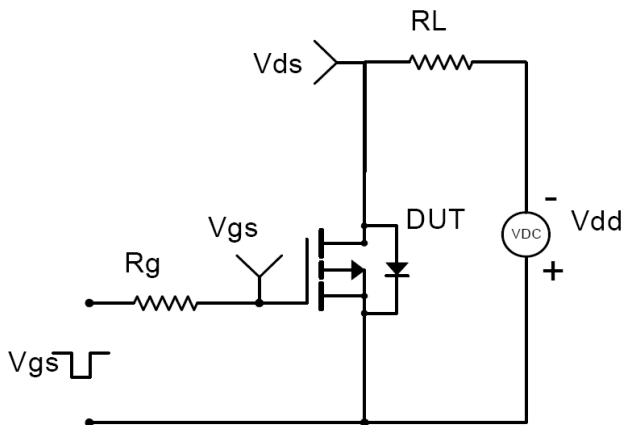
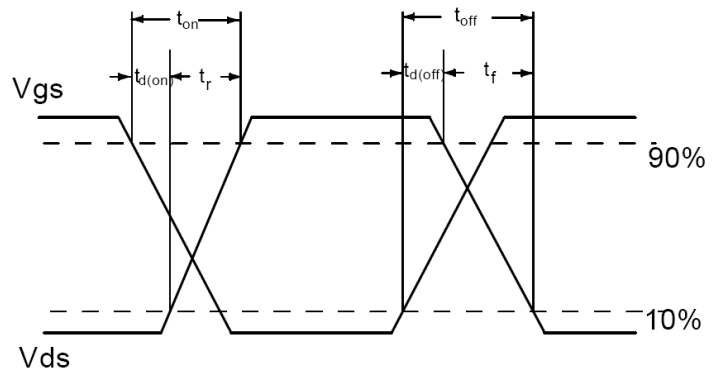
Symbol	Characterizes	Typ.	Max.	Units
$R_{\theta JA}$	Junction-to-ambient (t $\leq$ 10s) ④	—	60	°C/W

**Electrical Characterizes @ $T_A=25^{\circ}\text{C}$  unless otherwise specified**

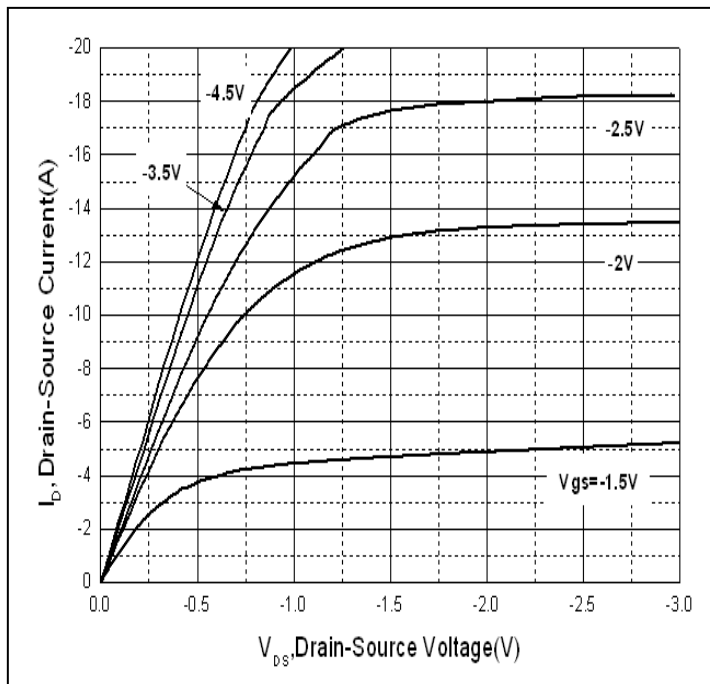
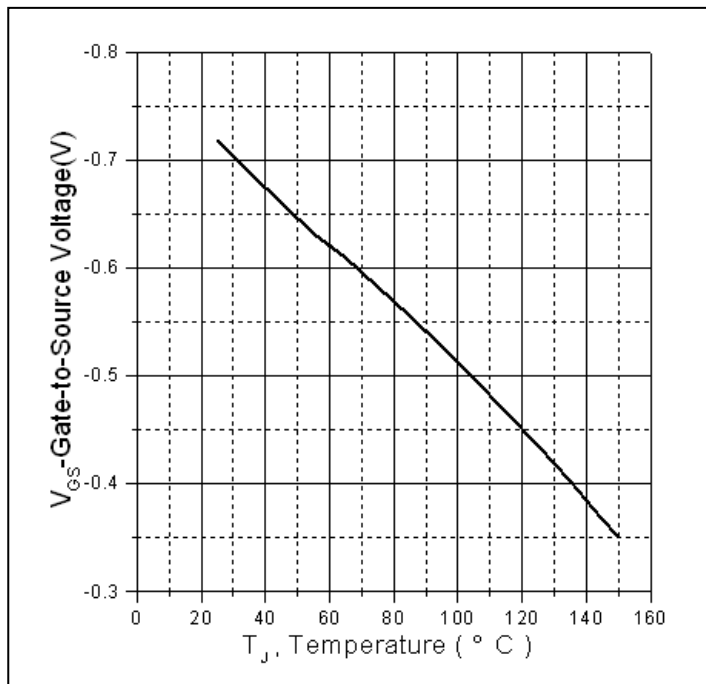
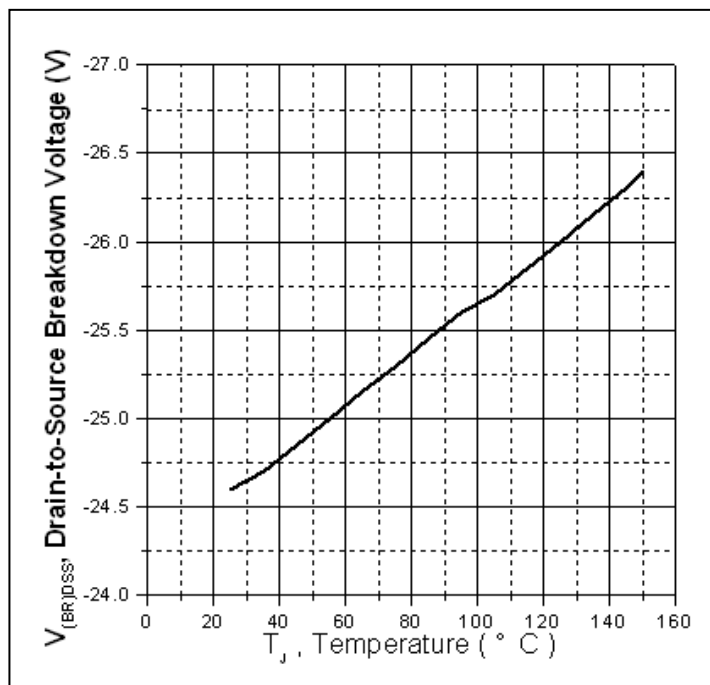
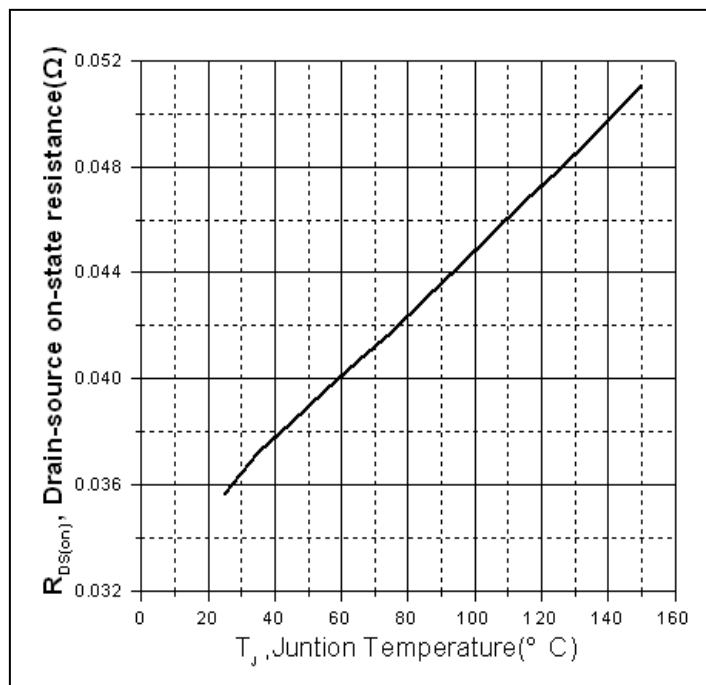
Symbol	Parameter	Min.	Typ.	Max.	Units	Conditions
$V_{(BR)DSS}$	Drain-to-Source breakdown voltage	-20	—	—	V	$V_{GS} = 0V, I_D = -250\mu A$
$R_{DS(on)}$	Static Drain-to-Source on-resistance	—	38	43	m $\Omega$	$V_{GS}=-4.5V, I_D = -4A$
		—	49	54		$V_{GS}=-2.5V, I_D = -4A$
		—	68	73		$V_{GS}=-1.8V, I_D = -2A$
$V_{GS(th)}$	Gate threshold voltage	-0.3	—	-1.0	V	$V_{DS} = V_{GS}, I_D = -250\mu A$
		—	-0.44	—		$T_J = 125^{\circ}\text{C}$
$I_{DSS}$	Drain-to-Source leakage current	—	—	-1	$\mu A$	$V_{DS} = -16V, V_{GS} = 0V$
		—	—	-50		$T_J = 125^{\circ}\text{C}$
$I_{GSS}$	Gate-to-Source forward leakage	—	—	10	$\mu A$	$V_{GS} = 8V$
		—	—	-10		$V_{GS} = -8V$
$Q_g$	Total gate charge	—	10	—	nC	$I_D = -4A,$ $V_{DS}=-10V,$ $V_{GS} = -4.5V$
$Q_{gs}$	Gate-to-Source charge	—	0.76	—		
$Q_{gd}$	Gate-to-Drain("Miller") charge	—	3.5	—		
$t_{d(on)}$	Turn-on delay time	—	10	—	ns	$V_{GS}=-4.5V, V_{DS} = -10V,$ $R_{GEN}=3\Omega,$
$t_r$	Rise time	—	8.4	—		
$t_{d(off)}$	Turn-Off delay time	—	29	—		
$t_f$	Fall time	—	13	—		
$C_{iss}$	Input capacitance	—	939	—	pF	$V_{GS} = 0V,$ $V_{DS} = -10V,$ $f = 1\text{MHz}$
$C_{oss}$	Output capacitance	—	132	—		
$C_{rss}$	Reverse transfer capacitance	—	108	—		

**Source-Drain Ratings and Characteristics**

Symbol	Parameter	Min.	Typ.	Max.	Units	Conditions
$I_S$	Continuous Source Current (Body Diode)	—	—	-5.5 ①	A	MOSFET symbol showing the integral reverse p-n junction diode.
$I_{SM}$	Pulsed Source Current (Body Diode)	—	—	-30	A	
$V_{SD}$	Diode Forward Voltage	—	-0.76	-1.0	V	$I_S=1A, V_{GS}=0V$
$t_{rr}$	Reverse Recovery Time	—	9.2	—	ns	$T_J = 25^{\circ}\text{C}, I_F = -4A,$
$Q_{rr}$	Reverse Recovery Charge	—	2.4	—	nC	$di/dt = 100A/\mu s$

**Test circuits and Waveforms**
**EAS test circuit:**

**Gate charge test circuit:**

**Switching time test circuit:**

**Switch Waveforms:**

**Notes:**

- ① Calculated continuous current based on maximum allowable junction temperature.
- ② Repetitive rating; pulse width limited by max. junction temperature.
- ③ The power dissipation PD is based on max. junction temperature, using junction-to-case thermal resistance.
- ④ The value of  $R_{\theta JA}$  is measured with the device mounted on 1 in 2 FR-4 board with 2oz. Copper, in a still air environment with  $T_A = 25^\circ\text{C}$

**Typical electrical and thermal characteristics**

**Figure 1: Typical Output Characteristics**

**Figure 2. Gate to source cut-off voltage**

**Figure 3. Drain-to-Source Breakdown Voltage Vs. Case Temperature**

**Figure 4: Normalized On-Resistance Vs. Case Temperature**

Typical electrical and thermal characteristics

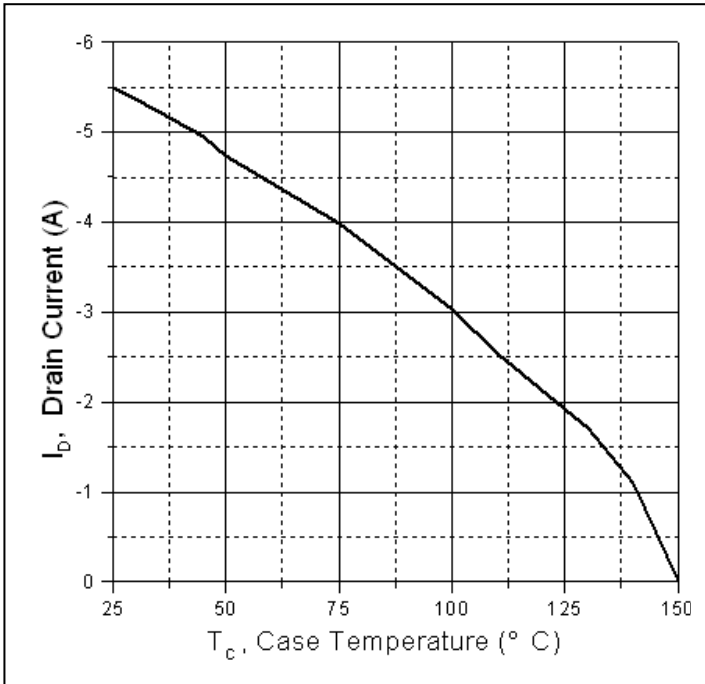


Figure 5. Maximum Drain Current Vs. Case Temperature

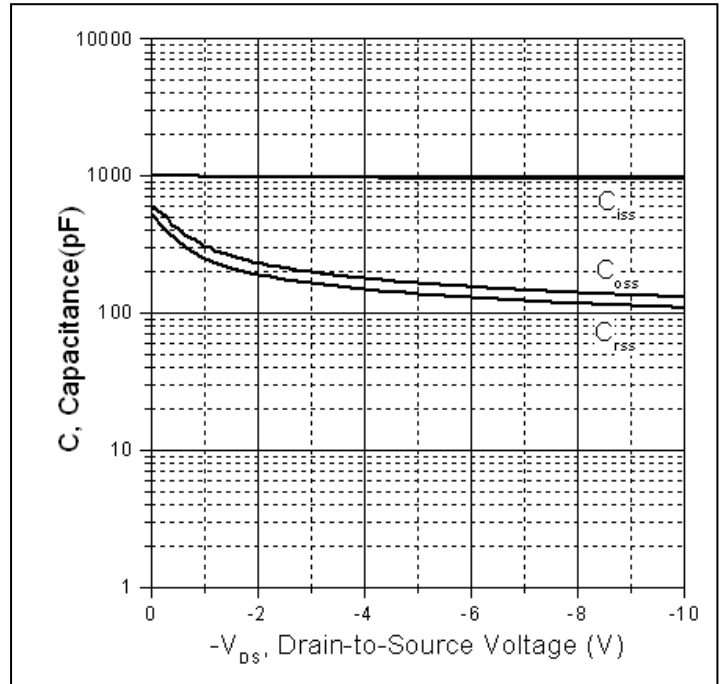


Figure 6. Typical Capacitance Vs. Drain-to-Source Voltage

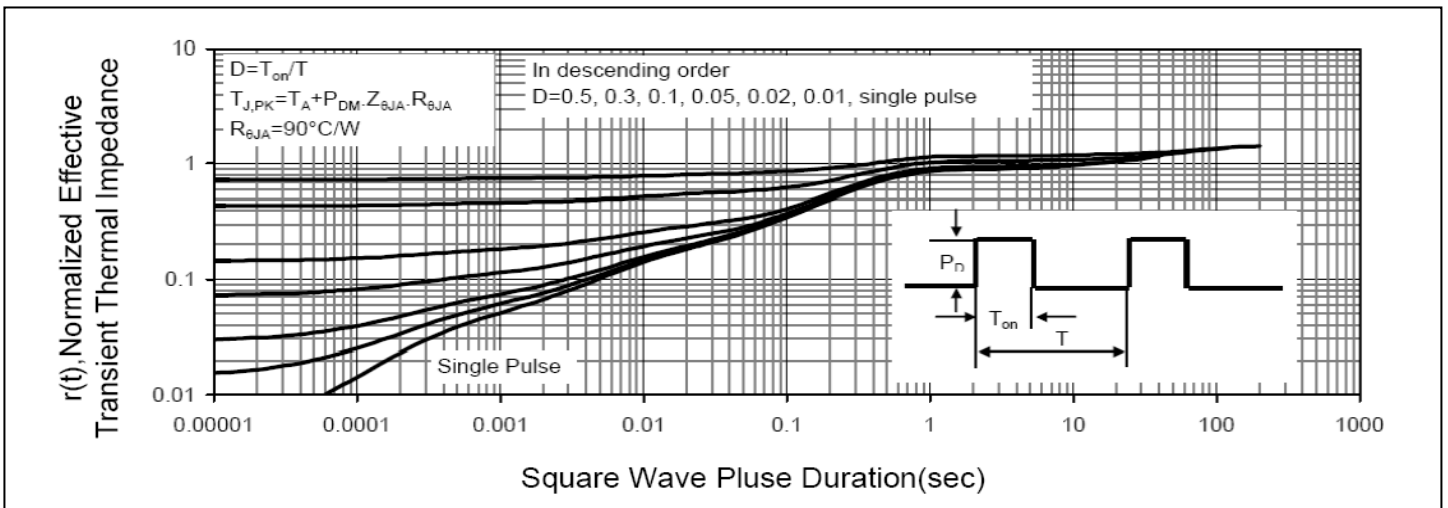
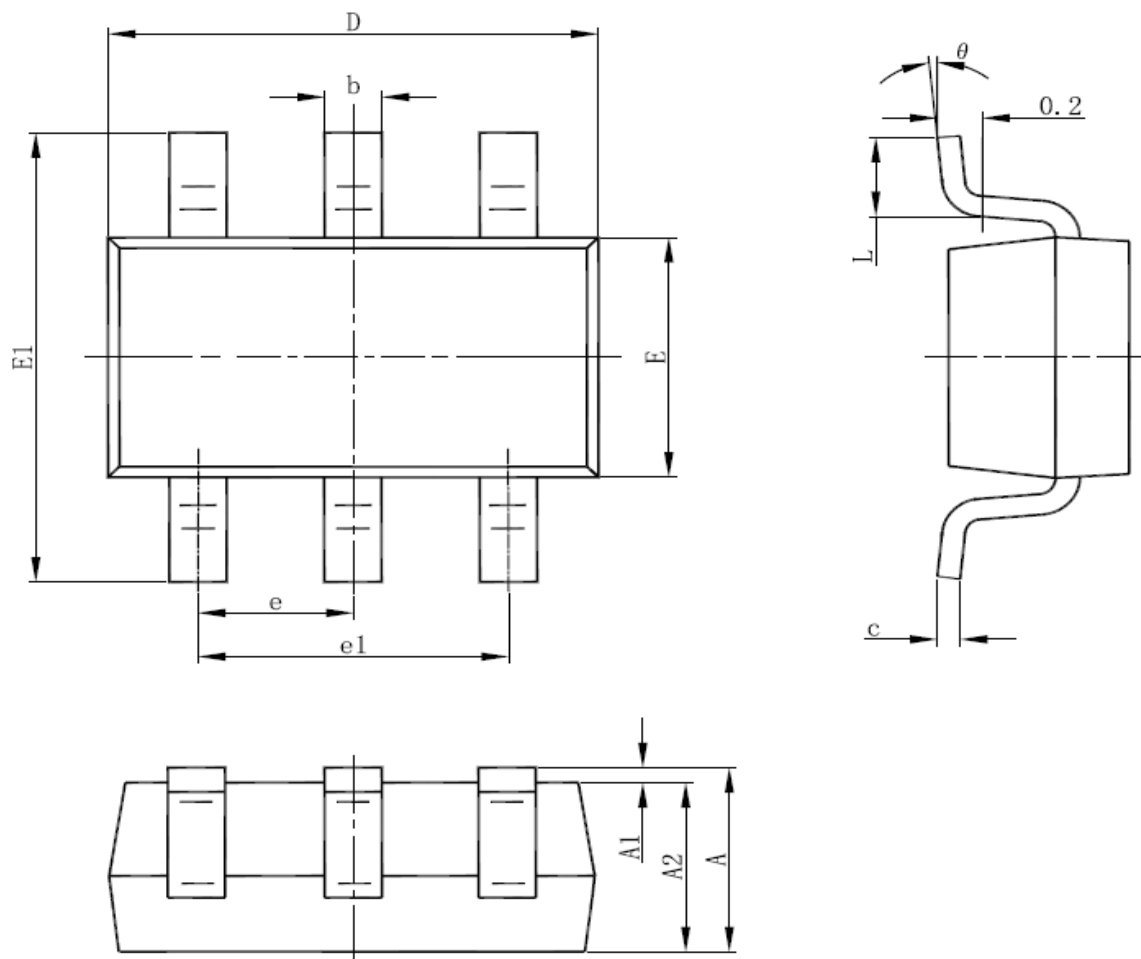


Figure7. Maximum Effective Transient Thermal Impedance Junction-to-Case

**Mechanical Data:**
**SOT-23-6L PACKAGE OUTLINE DIMENSION**


Symbol	Dimension In Millimeters		Dimension In Inches	
	Min	Max	Min	Max
A	1.050	1.250	0.041	0.049
A1	0.000	0.100	0.000	0.004
A2	1.050	1.150	0.041	0.045
b	0.300	0.500	0.012	0.020
c	0.100	0.200	0.004	0.008
D	2.820	3.020	0.111	0.119
E	1.500	1.700	0.059	0.067
E1	2.650	2.950	0.104	0.116
e	0.95(BSC)		0.037(BSC)	
e1	1.800	2.000	0.071	0.079
L	0.300	0.600	0.012	0.024
theta	0°	8°	0°	8°

**Ordering and Marking Information**
**Device Marking: 2437E**

**Package (Available)**  
**SOT23-6**  
**Operating Temperature Range**  
**C : -55 to 150 °C**

**Devices per Unit**

Package Type	Units/ Tape	Tapes/ Inner Box	Units/ Inner Box	Inner Boxes/ Carton Box	Units/ Carton Box
SOT23-6	3000	10	30000	4	120000

**Reliability Test Program**

Test Item	Conditions	Duration	Sample Size
High Temperature Reverse Bias(HTRB)	T <sub>j</sub> =125°C to 150°C @ 80% of Max V <sub>DSS</sub> /V <sub>CES</sub> /VR	168 hours 500 hours 1000 hours	3 lots x 77 devices
High Temperature Gate Bias(HTGB)	T <sub>j</sub> =150°C @ 100% of Max V <sub>GSS</sub>	168 hours 500 hours 1000 hours	3 lots x 77 devices

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Sales@silikron.com

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Technical@silikron.com

**Suzhou Silikron Semiconductor Corp.**

Building 11A Suchun Industrial Square, 428# Xinglong Street, Suzhou P.R. China

**TEL:** (86-512) 62560688

**FAX:** (86-512) 65160705

**E-mail:** Sales@silikron.com